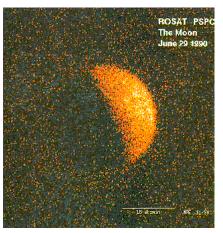
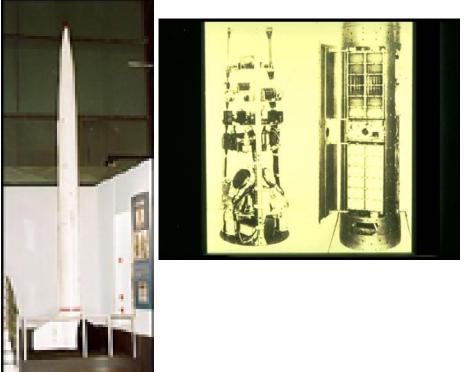


Optics Requirements for X-ray Astronomy & Developments at the Marshall Space Flight Center

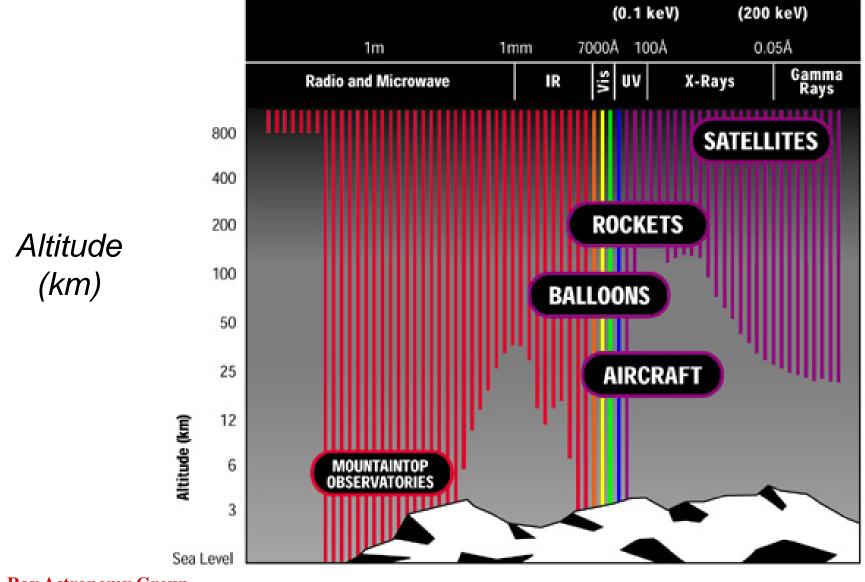
Birth of X-Ray Astronomy

- In 1962, Riccardo Giacconi and colleagues at AS&E flew sounding rocket to look at x-ray fluorescence from the moon
- Lunar signal was overshadowed by very strong emission from the Scorpious region
- Discovered the first extra-solar x-ray source,
 Sco X-1, and pervasive x-ray background
- This was the effective birth of x-ray astronomy





The Atmosphere Protects Us



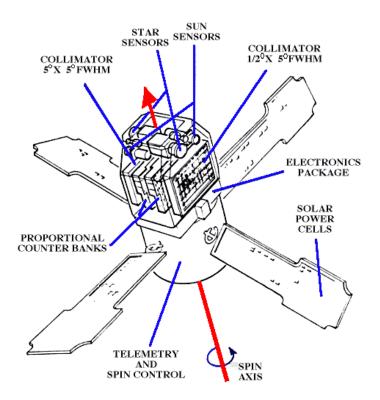


X-Ray Astronomy

First X-Ray Satellite

The UHURU spacecraft was launched in 1970

It weighed just 140 pounds, not much more than the rocket experiment

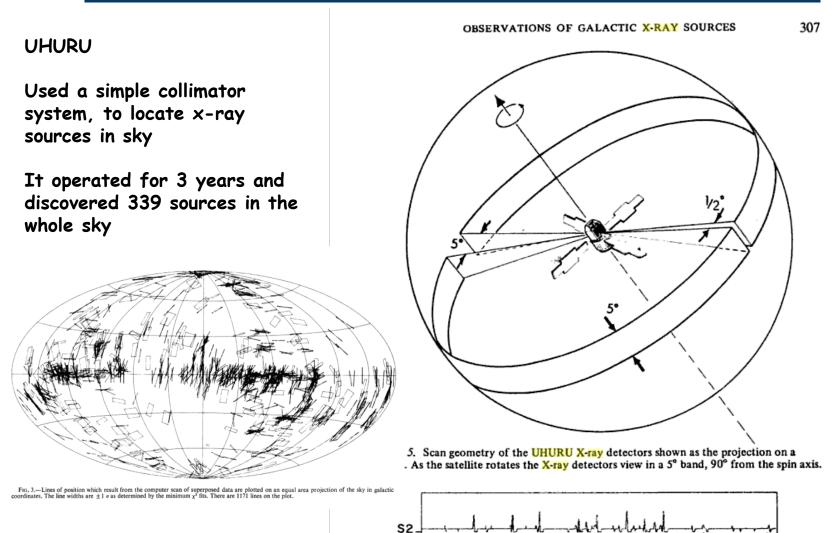








X-Ray Astronomy





X-Ray Astronomy

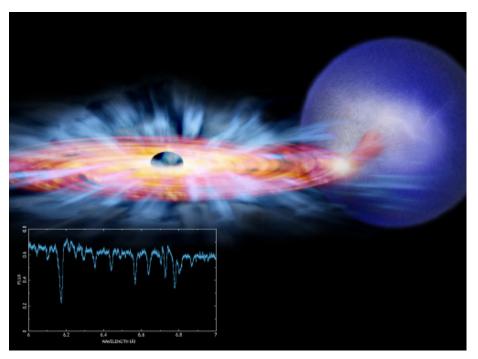
Early observations

From these early observations a picture emerged of a typical x-ray source:

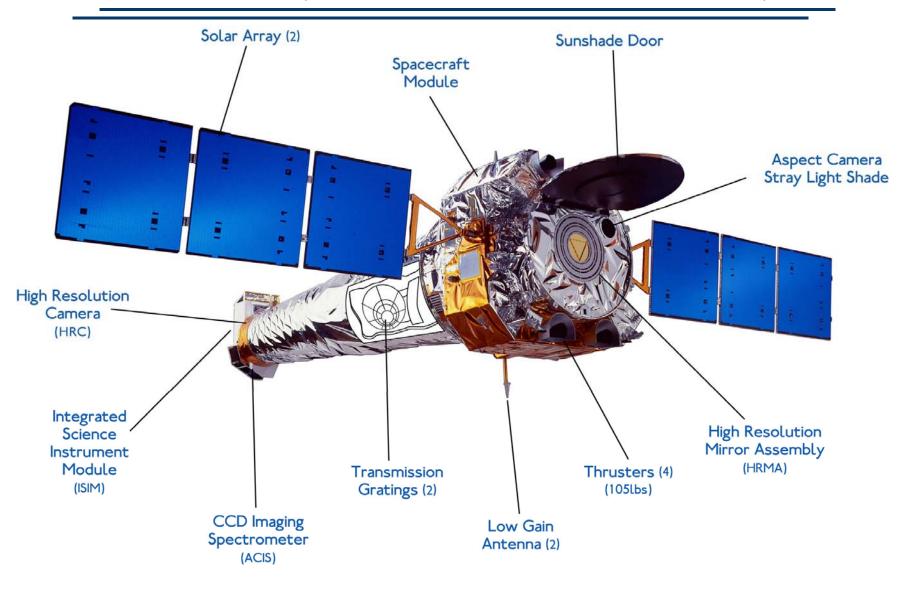
A compact object (neutron star, black hole, white dwarf) orbiting around a normal star

Matter streams down on to the compact object forming an accretion disk

As the matter spirals down and is compressed it gets very hot and emits x rays



Today ... The Chandra Observatory

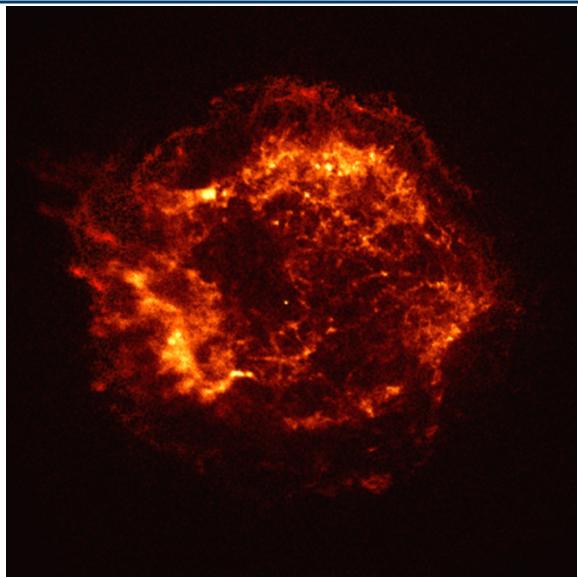


Today ... The Chandra Observatory

- School-bus-size x-ray observatory
- 100,000 times more powerful than UHURU
- Uses special mirrors to form highly detailed images
- In deep fields, more than 1000 new sources per square degree



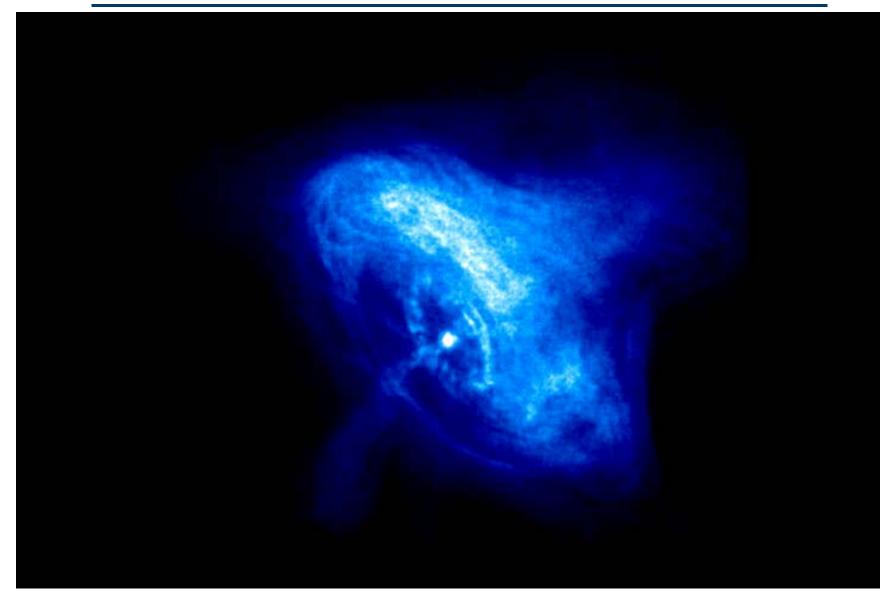
Chandra Images : Cas-A Supernova Remnant



Chandra Images : Center of our Galaxy



The Crab Nebula and its Pulsar



X-Ray Optics

Why focus x rays ?

1) Imaging - obvious

2) Background reduction

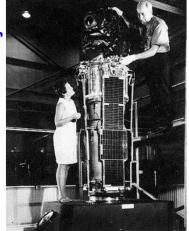
- Signal from cosmic sources very faint, observed against a large background
- Background depends on size of detector and amount of sky viewed
 - Concentrate flux from small area of sky on to small detector
 enormous increase in sensitivity

First dedicated x-ray astronomy satellite - UHURU mapped 340 sources with large area detector (no optics)

Chandra observatory - ~ same collecting area as UHURU

- 5 orders of mag more sensitivity --- 1,000 sources / sq degree in deep fields
- > 1 background count / keV year !

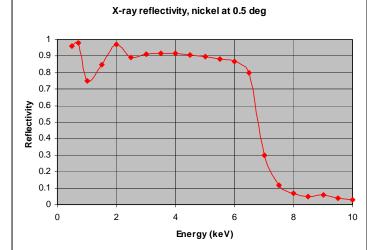
<u>X-Ray Optics has revolutionized x-ray astronomy</u>

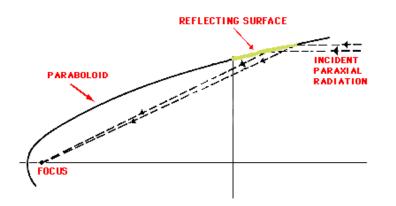


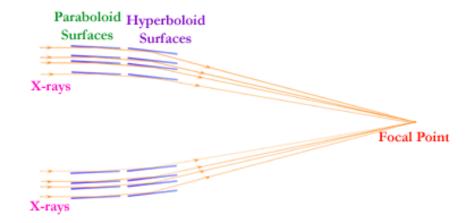
X-Ray Optics

- X Rays undergo total external reflection at shallow graze angles
 - Critical angle (away from absorption edges)
 - > ~ θ_c (deg) = 0.93 λ (nm) $\sqrt{\rho}$ (g/cm³)
- Can use this phenomenon in focusing x-ray telescopes

Reflect x rays to a common focus Single parabola gives severe off-axis distortions, ... Wolter-1 geometry adopted



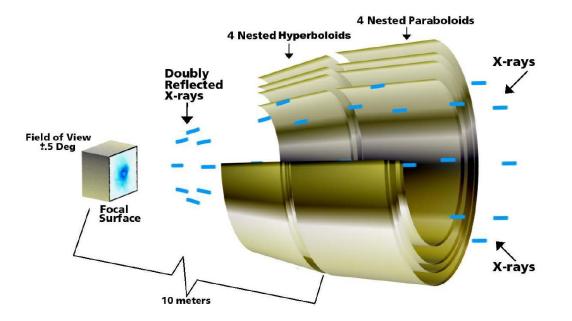




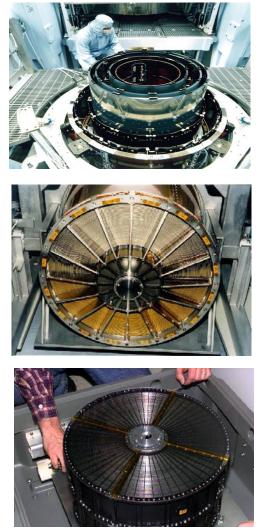
Approaches to Fabrication

• X-ray optics are very challenging to fabricate. Because of very short wavelength of x-rays the mirror surface must be smooth to ~ 0.5 nm rms.

• Also, for good angular resolution, the figure must be accurate to < 1 micron.



Approaches to Fabrication



Classical Optical grinding and polishing

Chandra, Rosat, Einstein Advantage: Superb angular resolution Disadvantage: High cost, large mass, difficult to nest

Electroformed Nickel Replication

XMM, JETX/Swift, SAX Advantage: High nesting factor, good resolution Disadvantage: Medium cost, mass (high density of nickel)

Segmented foil

ASTRO-E, ASTRO-F, ASCA, BBXRT Advantage: Light weight, low cost Disadvantage: Relatively poor angular resolution (arc-minute-level)

Approaches: Chandra



Approaches: Chandra

- Fabricated using thick ceramic, which is meticulously polished and figured, one shell at a time.
- Obtain superb angular resolution ----- 0.5 arcsec HPD
- But very costly to fabricate (\$500M) and very heavy (1000 kg)

• So, other approaches to x-ray optics have been used that trade the superb angular resolution for ease of fabrication and lighter weight (and cost)

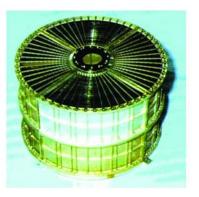
Approaches: Foil Optics

- Fabricated using very thin aluminum foils as reflectors. Foils held in slots in housing.
- Obtain poor angular resolution 1-2 arcminute HPD
- But extremely light weight allowing for many individual reflectors, and thus large collecting area





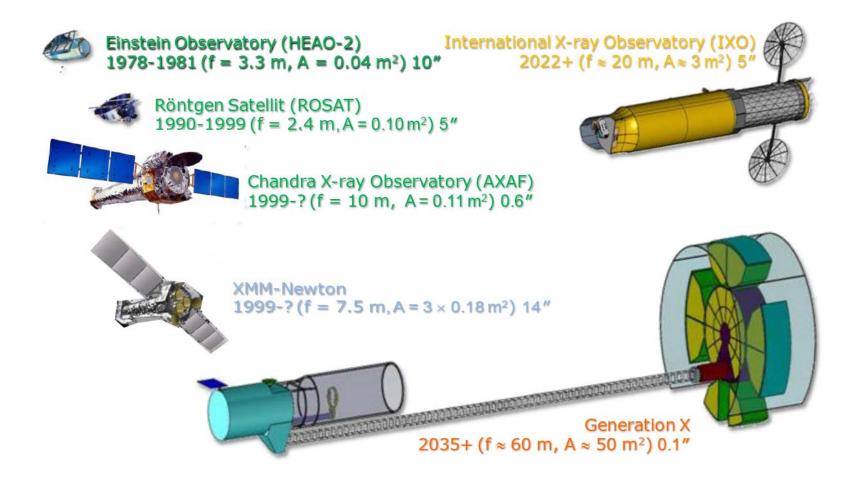




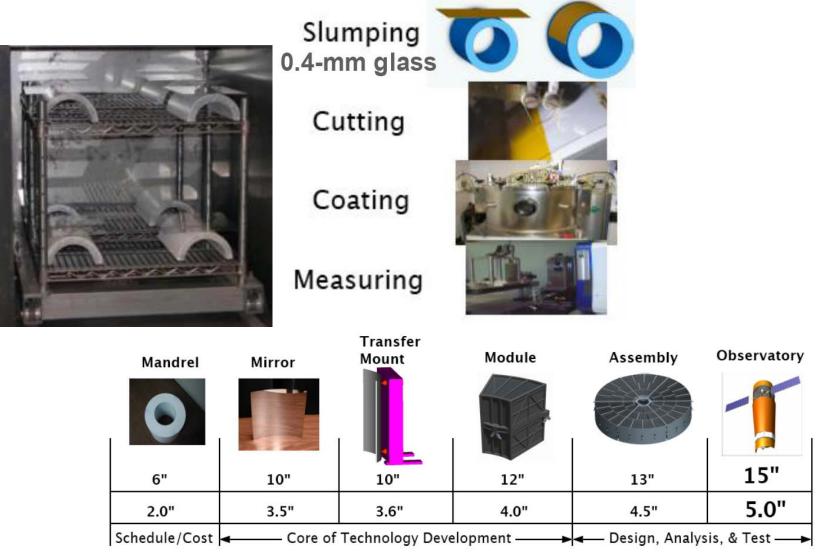
Approaches: Electroformed Nickel Replication (ENR)

- Electroform thin nickel shells from superpolished and figured masters (mandrels)
- Obtain intermediate level angular resolution (~ 15 arcsec HPD)
- But considerably less expensive to fabricate and considerably lighter
- Electroformed nickel optics are being fabricated at MSFC for various programs.

Challenges for Future Missions



Mirror Fabrication for (near) Future Missions



Mirrors for (far) Future Missions – Active Optics

How can we achieve sub-arcsec resolution with thin optics ?

One option is to utilize active control of mirror figure, as is done in optical astronomy

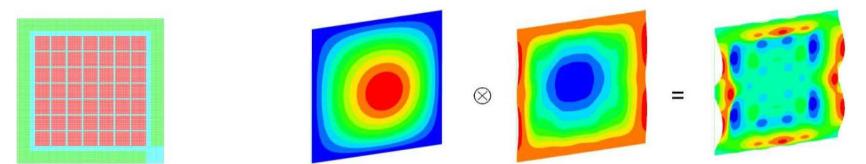


Figure 3: By appropriate adjustment of an array of surface-tangential actuators, a controlled deformation corrects the figure of a distorted mirror at the longer spatial wavelengths. The left panel schematically represents such an array on the back of a thin mirror segment. The right panel illustrates the application of a correction map to an error map, resulting in a mirror with low-spatial-frequency distortions removed.

Mirrors for (far) Future Missions – Active Optics

-1 -2 -3 -4

-0.06

diamond

-0.04

-0.05

-0.03

-0.02

-0.01

0

Lateral [m]

0.01

0.02

0.03

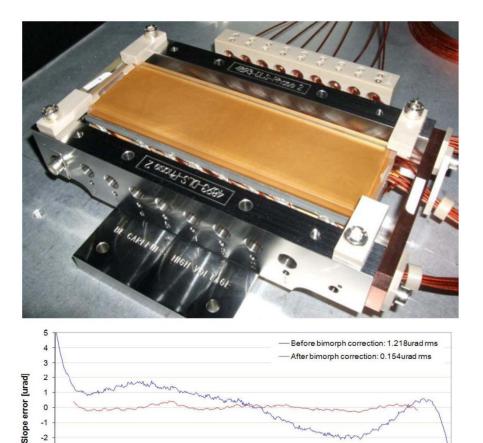
0.04

0.05

0.06

Technique has been used for synchrotron x-ray optics, but in its infancy in x-ray astronomy.

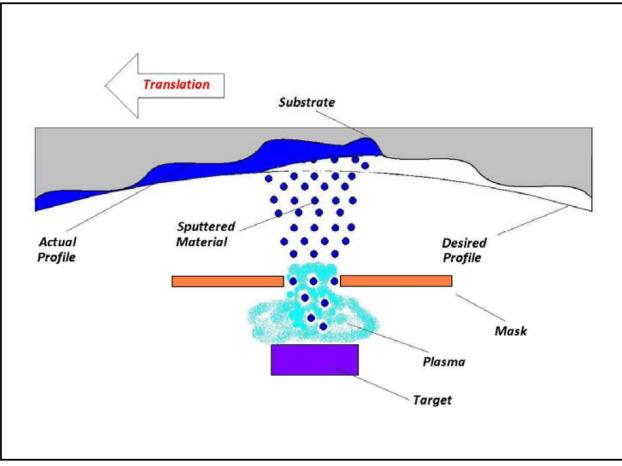
- Difficulty is the football-field-size areas that must be controlled.
- Algorithms needed that converge
- Power requirements and stability, etc

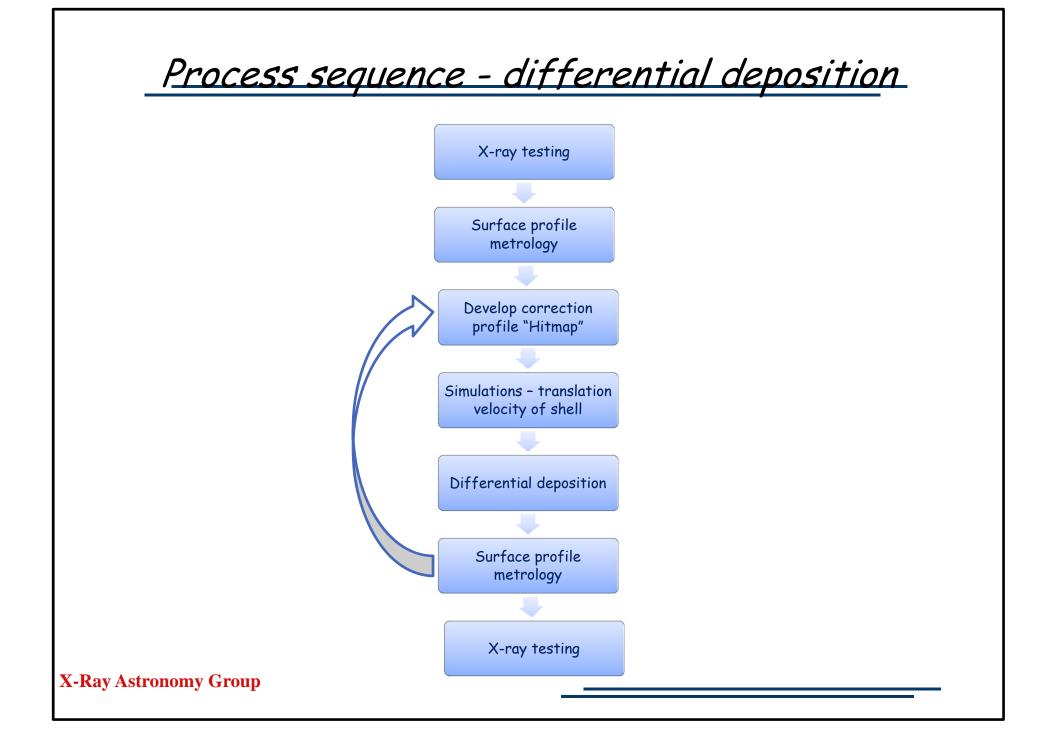


Mirrors for Future Missions – Differential Deposition

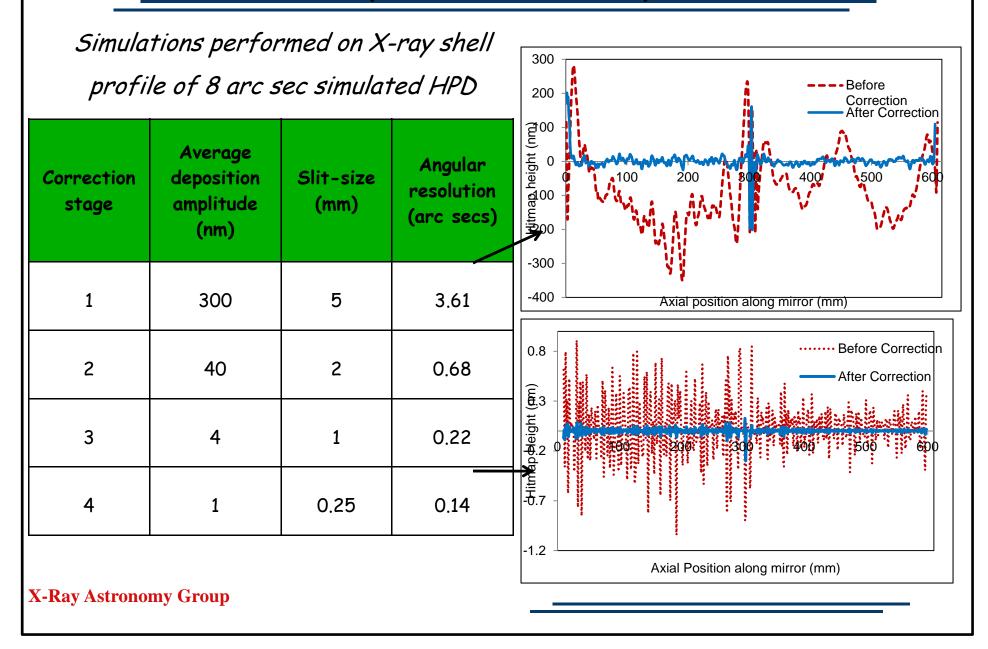
Vacuum deposit a filler material to compensate for figure imperfections

Proof of concept work underway at MSFC





Theoretical performance improvement



Possible practical limitations

Variation of sputtered beam profile along the length of mirror – particularly for short focal length mirrors

 Deviation in the simulated sputtered beam profile from actual profile, beam non-uniformities, etc

Positional inaccuracy of the slit with respect to mirror

• Stress effects

• Metrology uncertainty

X-Ray Astronomy Group

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Metrology limitation

Simulations performed on X-ray shell of 8 arc sec

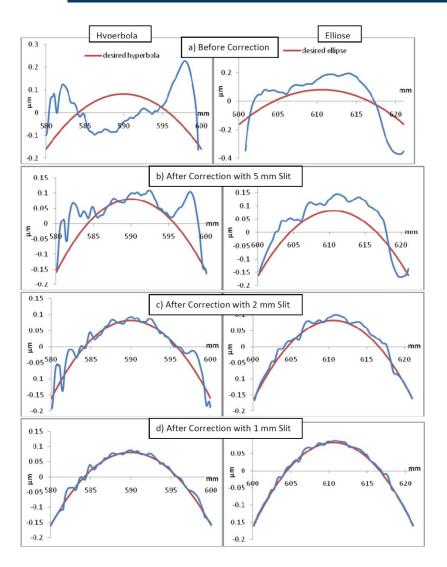
simulated HPD

Correction stage	Average deposition amplitude (nm)	Slit-size (mm)	Metrology uncertainty (nm)	Angular resolution (arc secs)	
			± 0	3.6	
1	300	5	± 10	3.6	
			± 50	7.3	
2			± 0	0.6	
	40	2	± 1	1	
	40	$\begin{array}{c} 2 \\ \pm 5 \\ \end{array} \begin{array}{c} 2 \\ \end{array}$			
			± 10	3.5	
3			± 0	0.2	
	4	1	± 0.5	0.2	
3	4	T	± 1	0.5	
			± 2	0.8	

 Potential for ~arc-second-level resolution - with MSFC's metrology equipment

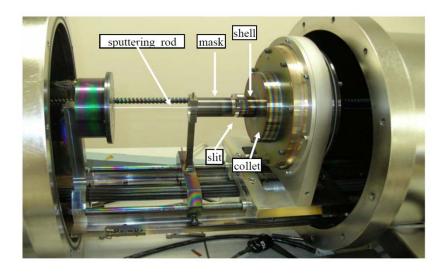
•Sub-arc sec resolution could be possible with the state-of-art metrology equipment

Mirrors for Future Missions – Differential Deposition



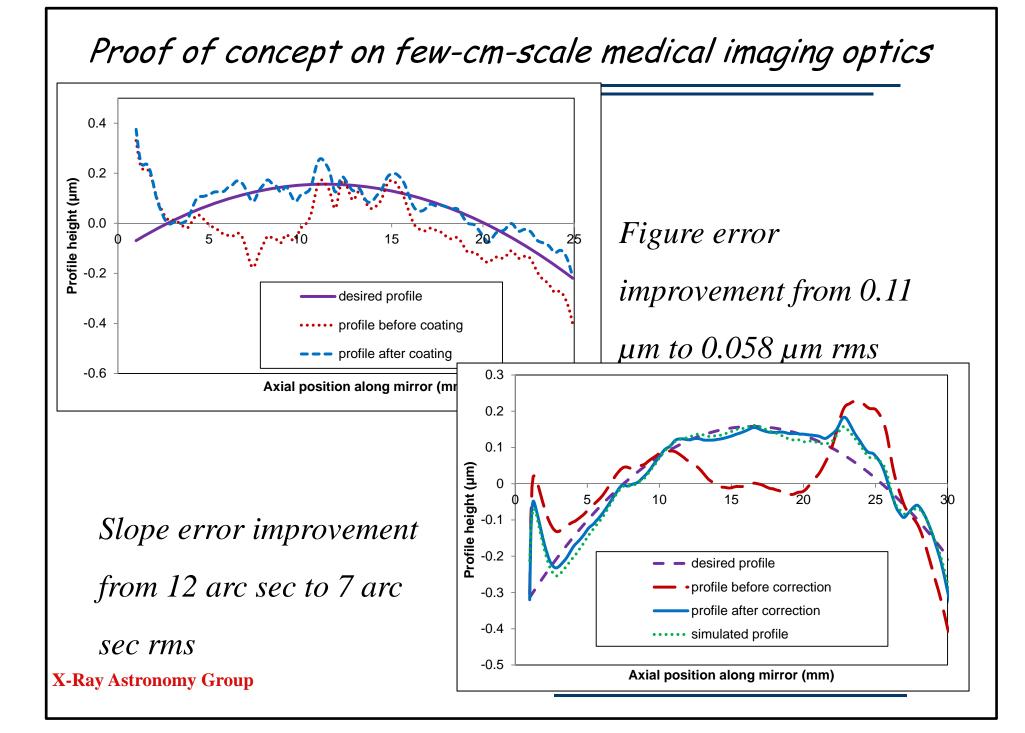
Correction stage	Average deposition amplitude (nm)	Slit- size (mm)	Amplitude uncertainty (nm)	Angular resolution (arcsec)
1	300	5	± 0	3.6
			± 10	3.6
			± 50	7.3
2	40	2	± 0	0.6
			± 1	1.0
			± 5	2.0
			± 10	3.5
3	4	1	± 0	0.2
			± 0.5	0.2
			± 1	0.5
			± 2	0.8

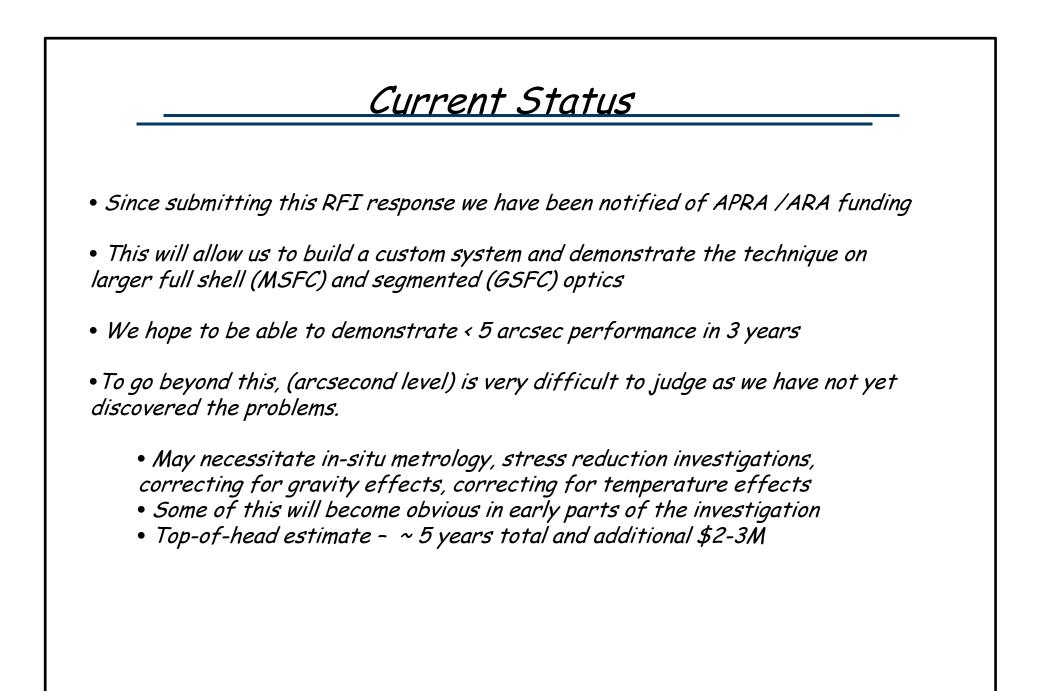
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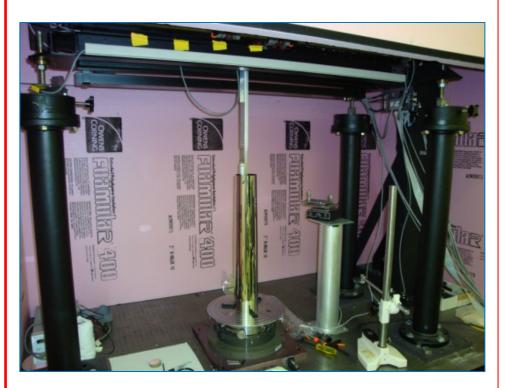
Material and process selection

Platinum-Xenon					Platinum-Argon				
power	pressure	roughness	deposition rate	power	pressure	roughness	deposition rate		
75	15	1.950	0.130	75	15	2.060	0.140		
90	15	2.043	0.230	90	15	1.933	0.190		
75	30	1.895	0.170	75	30	1.868	0.160		
90	30	1.810	0.250	90	30	2.083	0.220		
	1	Nickel-Xenon]	Nickel-Argon			
power	pressure	roughness	deposition rate	power	pressure	roughness	deposition rate		
75	15	1.915	0.290	75	15	1.995	0.180		
90	15	2.070	0.360	90	15	1.778	0.240		
75	30	3.093	0.240	75	30	2.260	0.220		
90	30	3.630	0.310	90	30	2.210	0.290		
	Tı	ungsten-Xenon		Tungsten-Argon					
power	pressure	roughness	deposition rate	power	pressure	roughness	deposition rate		
75	15	1.965	0.300	75	15	1.900	0.120		
75	30	1.805	0.290	75	30	2.125	0.290		
	30	1.993	0.370	90	30	-	-		
90	50			ř.			1		
90 75	50	2.075	0.290	75	50	1.998	0.310		





Long Trace Profiler



© Time taken to measure is about 5 mins for 300 mm sample length

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•Pencil beam interferometry

•Measure spatial wavelengths starting from 1 mm upto several 100's of mm

•Laser beam scans point-by- point - slope data

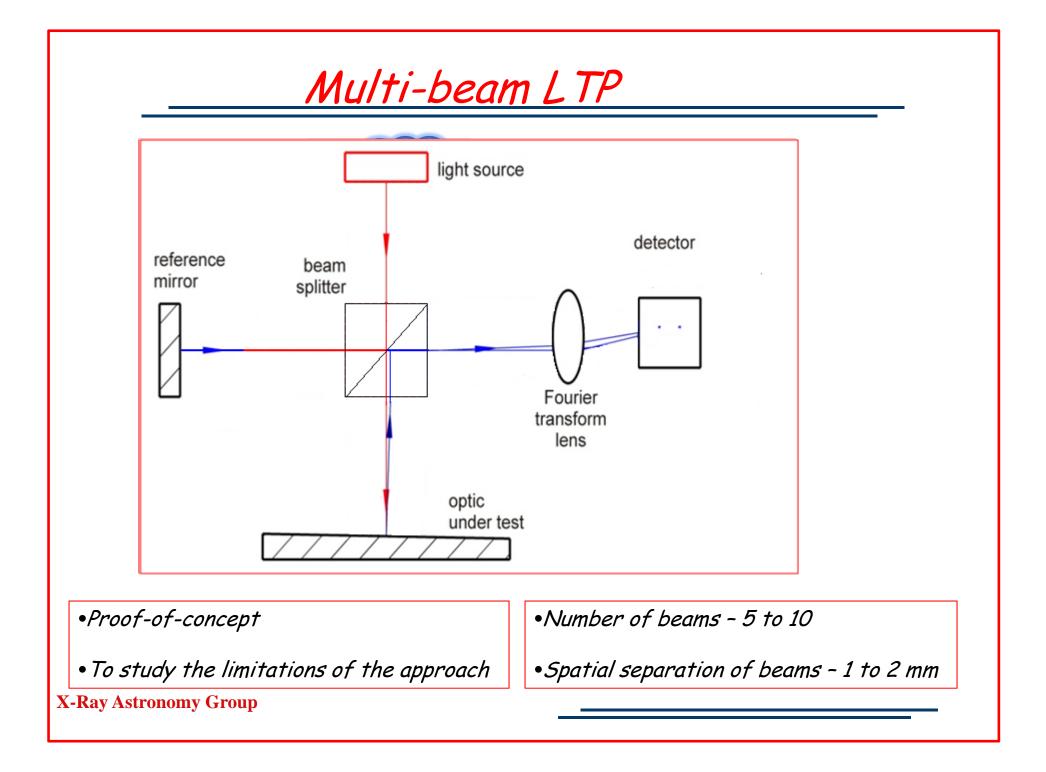
•Position of the beam at the detector direct measure of the slope

•Accuracies possible <1 urad

•Multiple measurements - 2D topography

Increase the speed ?

- Make use of advanced technology
- Higher resolution 2D detectors
- Stable optical sources
- Increase the speed & accuracies of measurements
- Higher density data complete information of mandrel or shell
- Multiple beams simultaneous measurements?



Multi-beam LTP Requirements

• Target - decrease the time of measurement - reasonable accuracy

• Existing systems

- linear array detector $25 \mu m \times 2.5 mm$ pixel size
- 1 m focal length FT lens
- Lens and detector \rightarrow 0.25 μ rad

• 2D detector requirements

- multiple beams in one plane and beam translation on other plane
- angular range +/- 15 mrad
- Detector atleast 20 mm X 20 mm area
- $< 8 \mu m$ pixel size

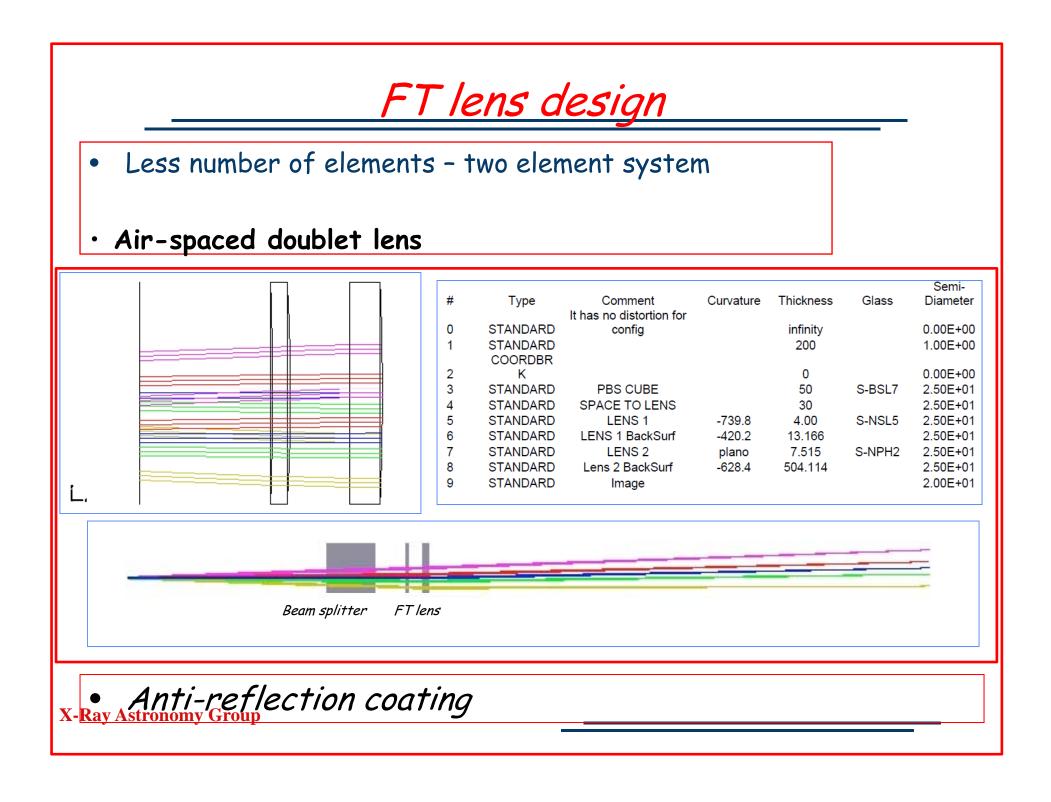
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fl (mm)	500	550	600	700	800	
pixel (µm)						
4	0.12	0.11	0.10	0.09	0.08	
8	0.24	0.22	0.20	0.17	0.15	
10	0.30	0.27	0.25	0.21	0.19	
14	0.42	0.38	0.35	0.30	0.26	
18	0.54	0.49	0.45	0.39	0.34	

*Resolution (*µrad)

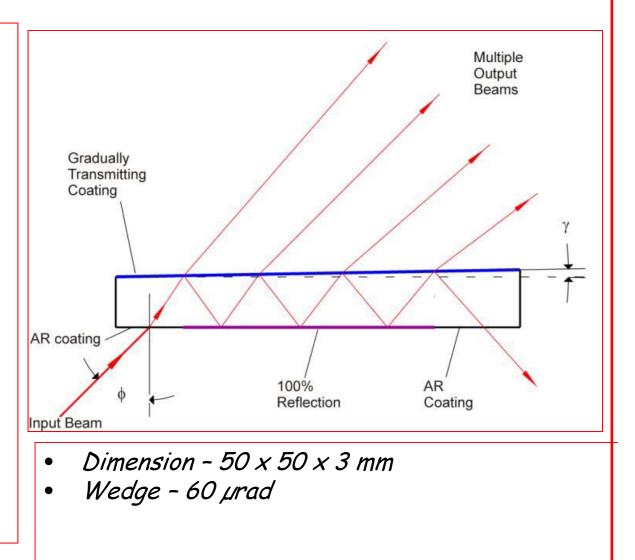
2D CCD detector & FT lens

- Detector Procured (1st Vision's JAI AM-1600GE)
 - 36 mm × 24 mm area
 - 7.4 \times 7.4 μ m pixel size
 - 3.04 fps
- Custom designed FT lens
 - 500 mm focal length
 - 50 mm diameter
 - Low distortion minimize the effects of lens on systematic errors



Multiple beam generation

- Multiple beams of almost equal intensity
- Spatial separation (2.4 mm)
- Angular separation (250 µrad)
- Wedged etalon approach
- Customized coating on one side
- 100% reflection coating on the other

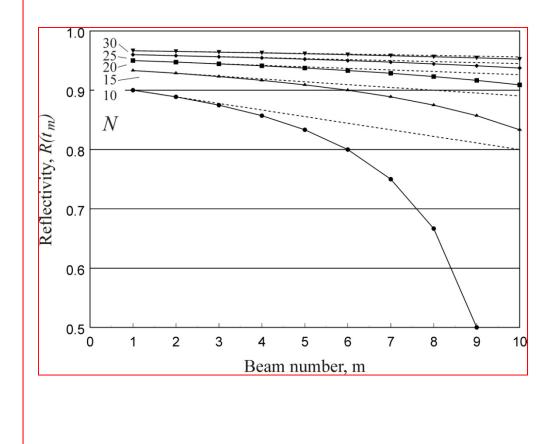


Coating - wedged etalon

Possible approaches

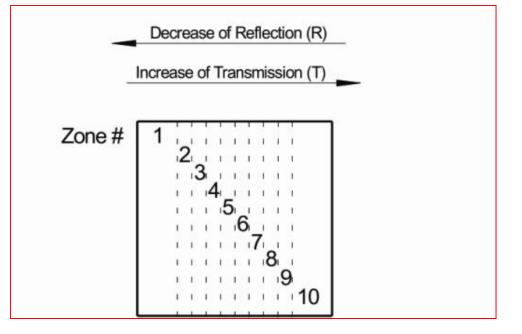
- •Continuous ideal gradient coating
- •Linear approximation to ideal
- •Multilayers

•Discrete coatings - each with constant reflectivity



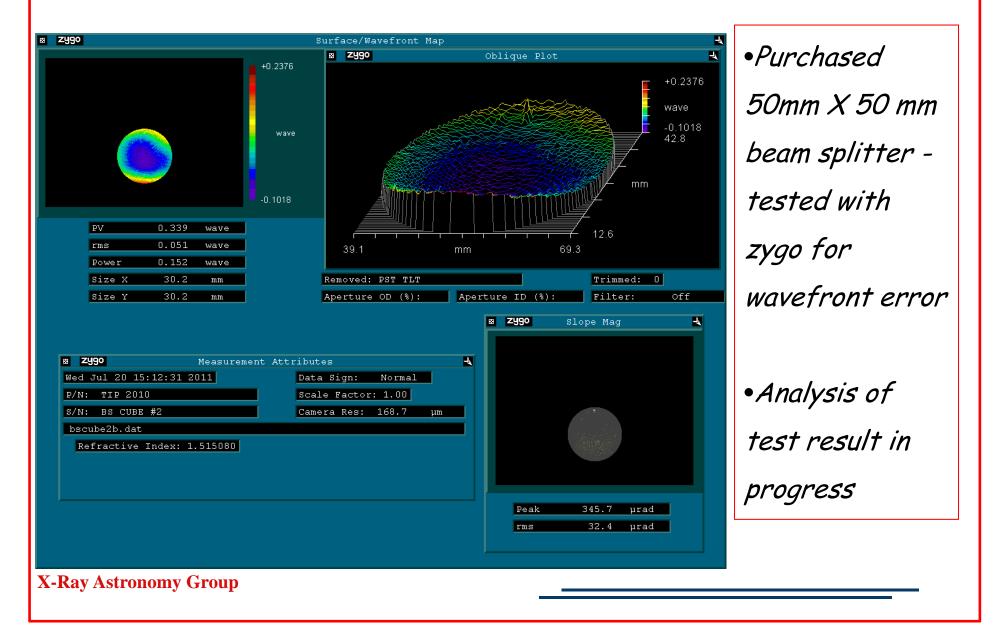
Multiple beam generation - wedged etalon

• Silver coating with step reflectivity approach



Zone	1	2	3	4	5	6	7	8	9	10
R _Z , %	93.33	92.86	92.31	91.67	90.91	90.00	88.89	87.50	85.71	83.33
T _Z , %	6.67	7.14	7.69	8.33	9.09	10.00	11.11	12.50	14.29	16.67





Software

- Berkeley National Labs provided software code
- 3 beams being adapted to new detector for multiple beams Maxima of single peak
- Tests are underway to check the speed of readout & processing 0.5 fps for full frame of 4872x3248 1.3 fps for partial frame of 4872x800

